528 Rec'd PC

IN THE UNITED STATES PATENT AND TRADEMARK OF

In re Application of:

Atsushi ITO, Yasuji HIRAMATSU, Yasutaka ITO, and Masakazu FURUKAWA

Appln. No.: (Not Yet Designated) Group Art Unit: Unknown

Filed: October 24, 2000

Examiner: Unknown

For: WAFER PROBER

October 24, 2000

## PRELIMINARY AMENDMENT

Assistant Commissioner for Patents Washington, D. C. 20231

Sir:

Prior to examination of the above-identified application, please amend the application as follows:

## IN THE CLAIMS:

In claim 3, at line 1, delete "or 2".

5. (twice amended) A wafer prober according to claim 1 [which comprises a ceramic substrate and a conductor layer formed on the surface thereof], wherein said ceramic substrate is equipped with a Peltier device. thererodedric davice

(twice amended) A wafer prober according to claim 1 [which comprises a ceramic substrate and a conductor layer formed on the surface thereof], wherein on said ceramic substrate, channels are formed.